

Notice of References Cited	Application/Control No. 10/644,362		Applicant(s)/Patent Under Reexamination PAIST ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	B	US-6,724,265	04-2004	Humphreys, Scott Robert	331/17
X	C	US-6,700,945	03-2004	Maeda, Minoru	375/376
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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